The Path to Successful Production
Guest Editor’s Introduction Jack Arabian

Inductive Fault Analysis of MOS Integrated Circuits
John P. Shen, W. Maly, and F. Joel Ferguson
ICA is a methodology for predicting and extracting faults in a MOS IC or subcircuit; such fault lists can be used to evaluate the efficacy of test sets and the generation of test patterns.

PROD: A VLSI Fault Diagnosis System
Peter Odryna and Andrzej J. Strojwas
Higher yield and lower costs can be realized by using this diagnostic system to detect and eliminate process disturbances before manufacturing.

Noise Problems in Testing VLSI Hardware
Kofi E. Torku and Dave A. Kiesling
Design for testability—the design of VLSI chips and testers to reduce noise-related failures at manufacturing test—will minimize costly production problems.

Autoprobing on the L200 Functional Tester
Tim Moore and Stephen Garner
Designed for the diagnostic verification of modules, this automatic system reduces manual probe time by a factor of ten—increasing tester throughput by decreasing average diagnostic time.

Operational Life Testing of Electronic Components
David F. Farnholtz
AT&T’s monitor of electronic “infant mortality” enhances product reliability while saving money.

Teradyne’s J967 VLSI Test System: Getting VLSI to the Market on Time
Wayne Ponik
Labeling bad devices as good loses face; labeling good devices as bad loses money. A cost-effective test system separates good devices from bad.

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